

Features

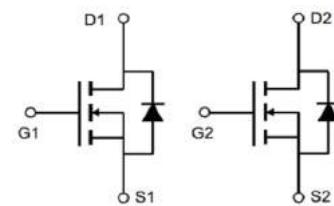
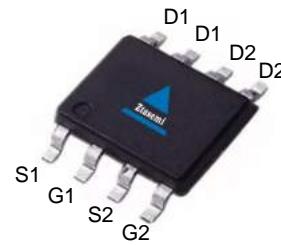
- Dual N-Channel
- Advanced Trench Technology
- Excellent $R_{DS(ON)}$ and Low Gate Charge
- Lead Free
- 100% EAS Tested



Part ID	Package Type	Marking	Packing
ZT9926	SOP-8	9926	4000pcs/reel

V_{DS}	20	V
$R_{DS(on),TYP}$ @ $V_{GS}=4.5V$	14	$m\Omega$
$R_{DS(on),TYP}$ @ $V_{GS}=2.5 V$	18	$m\Omega$
I_D	6.5	A

SOP-8



Absolute Maximum Ratings $T_A = 25^\circ C$, unless otherwise specified

Symbol	Parameter	Rating	Unit	
Common Ratings ($T_c=25^\circ C$ Unless Otherwise Noted)				
V_{GS}	Gate-Source Voltage	± 12	V	
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	20	V	
T_J	Maximum Junction Temperature	150	$^\circ C$	
T_{STG}	Storage Temperature Range	-55 to 150	$^\circ C$	
I_{DM}	Drain Current-Continuous@ Current-Pulsed (Note 1)	$T_c=25^\circ C$	26	A
Mounted on Large Heat Sink				
I_D	Drain Current-Continuous	$T_c=25^\circ C$	6.5	A
		$T_c=100^\circ C$	4	A
P_D	Maximum Power Dissipation	1.6	W	
$R_{\theta JA}$	Thermal Resistance Junction-Ambient	76	$^\circ C/W$	
Drain-Source Avalanche Ratings				
EAS	Avalanche Energy, Single Pulsed (Note 2)	25	mJ	



Electrical Characteristics ($T_J=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Condition	Min	Typ	Max	Unit
Static Electrical Characteristics @ $T_J=25^\circ C$ (unless otherwise stated)						
V(BR)DSS	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	20	--	--	V
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=20V, V_{GS}=0V$	--	--	1	μA
I _{GSS}	Gate-Body Leakage Current	$V_{GS}=\pm 12V, V_{DS}=0V$	--	--	± 100	nA
V _{G(S)th}	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	0.5	0.7	1.0	V
R _{D(on)}	Drain-Source On-State Resistance	$V_{GS}=4.5V, I_D=6.5A$	--	14	18	$m\Omega$
R _{D(on)}	Drain-Source On-State Resistance	$V_{GS}=2.5V, I_D=5A$	--	18	23	$m\Omega$

Dynamic Electrical Characteristics @ $T_J = 25^\circ C$ (unless otherwise stated)

C _{iss}	Input Capacitance	$V_{DS}=10V, V_{GS}=0V, f=1MHz$	--	649	--	pF
C _{oss}	Output Capacitance		--	120	--	pF
C _{rss}	Reverse Transfer Capacitance		--	106	--	pF
Q _g	Total Gate Charge	$V_{DD}=10V, I_D=3.5A, V_{GS}=4.5V$	--	8.8	--	nC
Q _{gs}	Gate-Source Charge		--	1.1	--	nC
Q _{gd}	Gate-Drain Charge		--	2.4	--	nC

Switching Characteristics

T _{d(on)}	Turn-on Delay Time	$V_{DD}=10V, I_D = 3.5A, R_G=3.0\Omega, V_{GS}=4.5V$	--	10.6	--	ns
T _r	Turn-on Rise Time		--	30.1	--	ns
T _{d(off)}	Turn-Off Delay Time		--	30.2	--	ns
T _f	Turn-Off Fall Time		--	34.8	--	ns

Source-Drain Diode Characteristics @ $T_J = 25^\circ C$ (unless otherwise stated)

I _s	Diode Forward Current		--	--	6.5	A
V _{SD}	Forward on voltage	$I_S=6.5A, V_{GS}=0V$	--	--	1.2	V
T _{rr}	Reverse Recovery Time	$I_F= 6A, dI/dt=100A/\mu s$	--	8.5	--	ns
Q _{rr}	Reverse Recovery Charge		--	2	--	nC

Notes:

1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature
2. EAS condition : Starting $T_J=25^\circ C$, $V_{DD}=10V$, $V_G=10V$, $L=0.5mH$, $R_g=25\Omega$, $I_{AS}=10A$
3. Pulse Test: Pulse Width $\leq 300\mu s$, Duty Cycle $\leq 0.5\%$



Typical Performance Characteristics

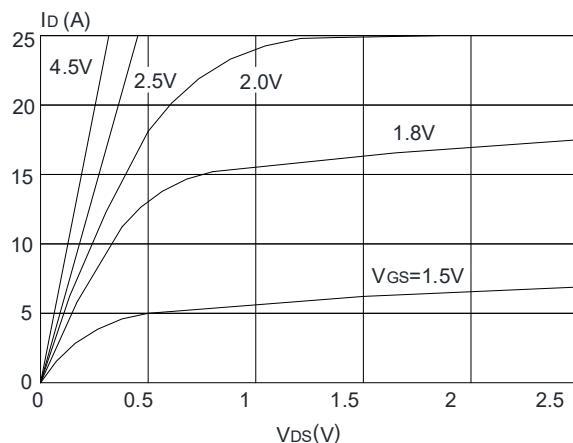


Figure 1: Output Characteristics

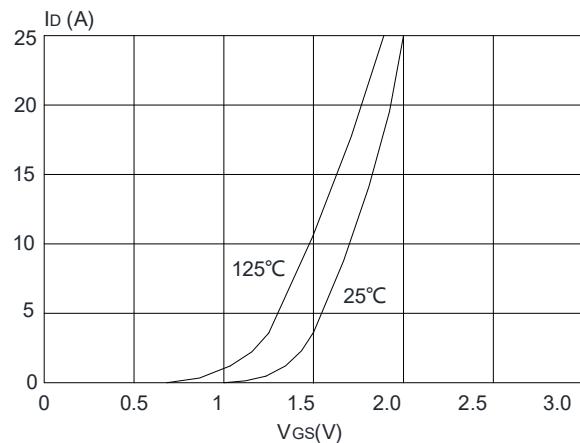


Figure 4: Typical Transfer Characteristics

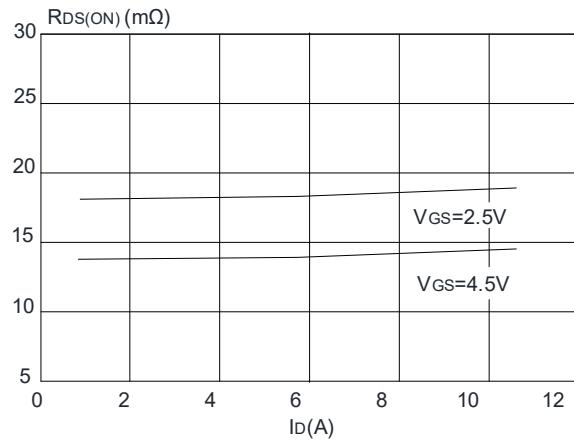


Figure 2: On-resistance vs. Drain Current

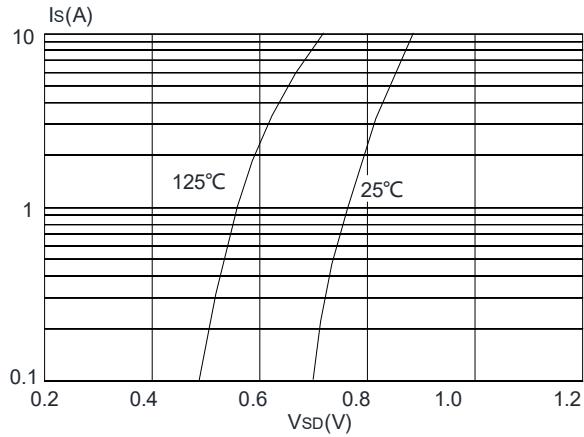


Figure 5: Body Diode Characteristics

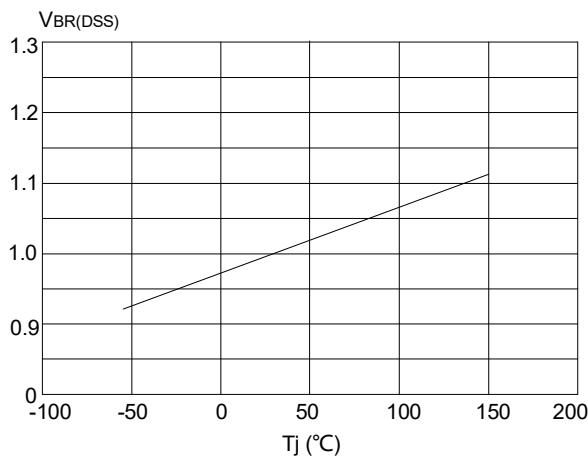


Figure 3: Normalized Breakdown Voltage vs. Junction Temperature

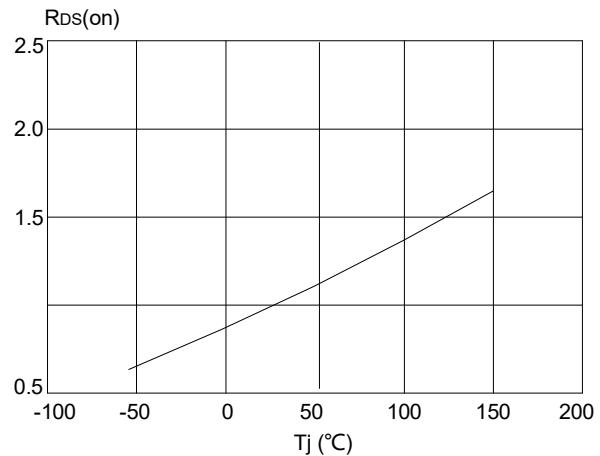


Figure 6: Normalized on Resistance vs. Junction Temperature

Typical Performance Characteristics

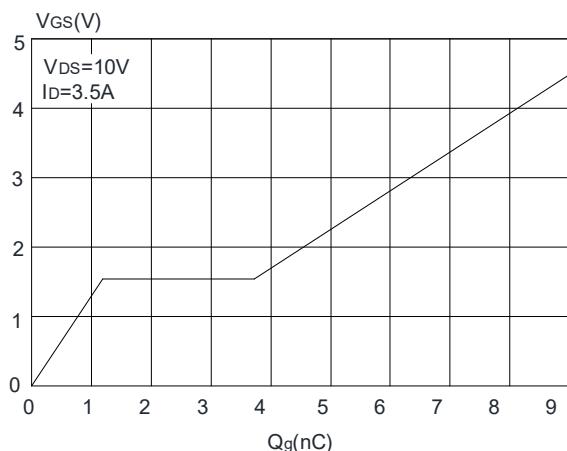


Figure 7: Gate Charge Characteristics

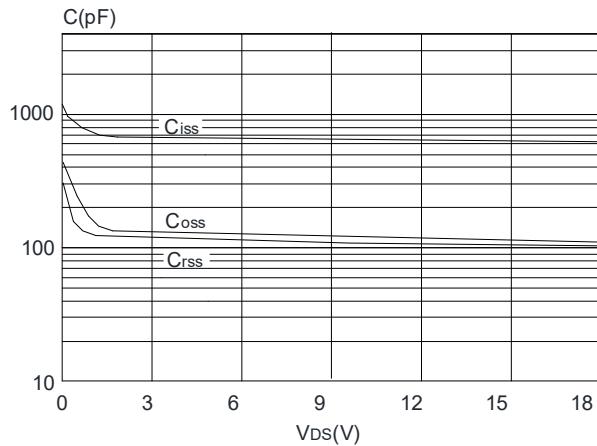


Figure 9: Capacitance Characteristics

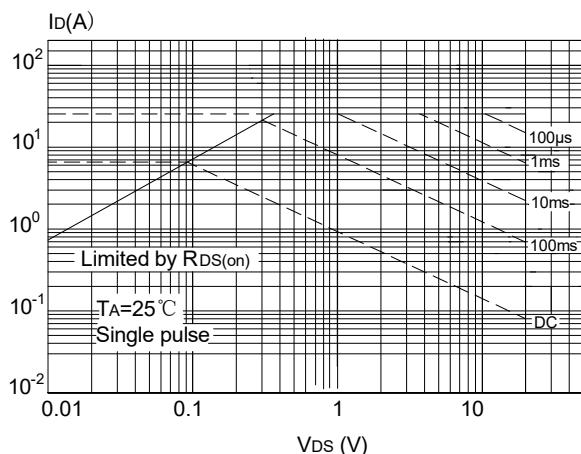


Figure 8: Maximum Safe Operating Area

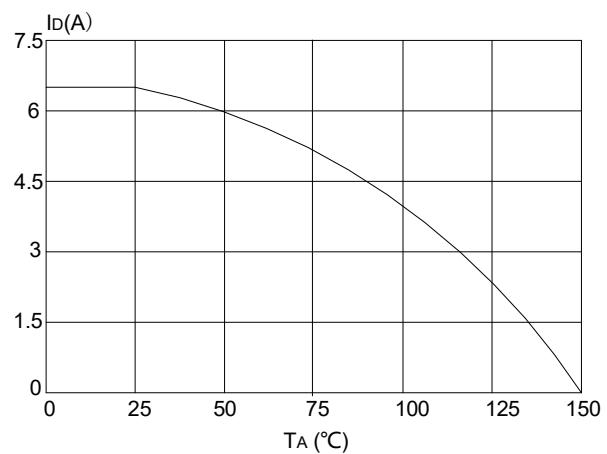


Figure 10: Maximum Continuous Drain Current vs Ambient Temperature

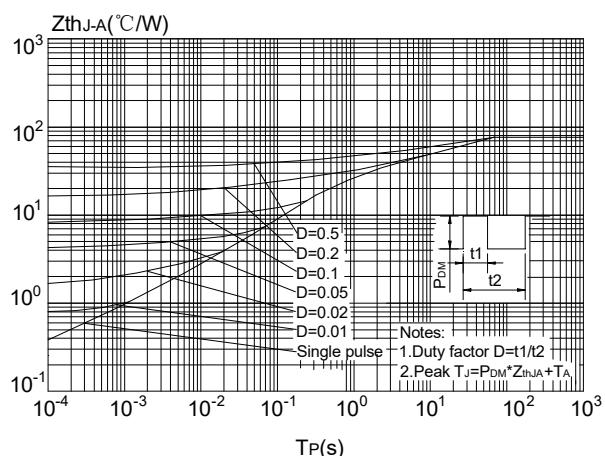


Figure 11: Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

Test Circuit

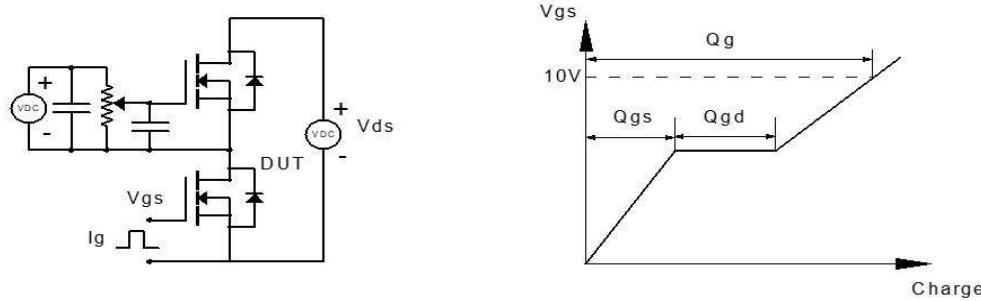


Figure 1: Gate Charge Test Circuit & Waveform

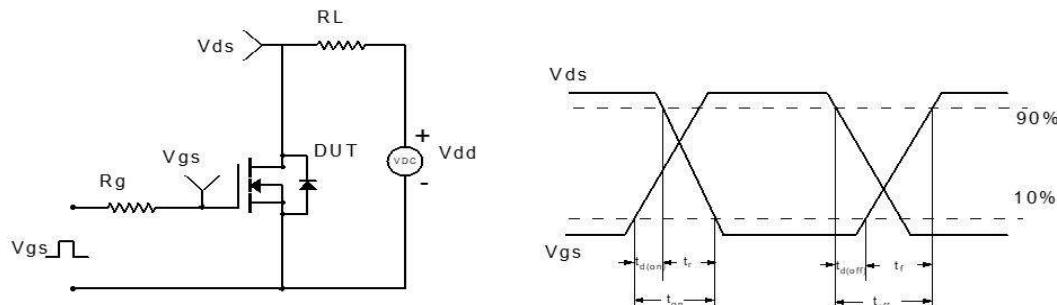


Figure 2: Resistive Switching Test Circuit & Waveform

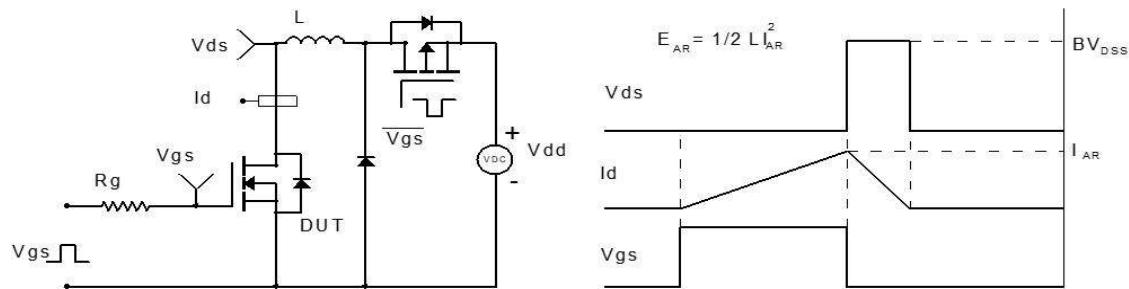


Figure 3: Unclamped Inductive Switching Test Circuit & Waveform

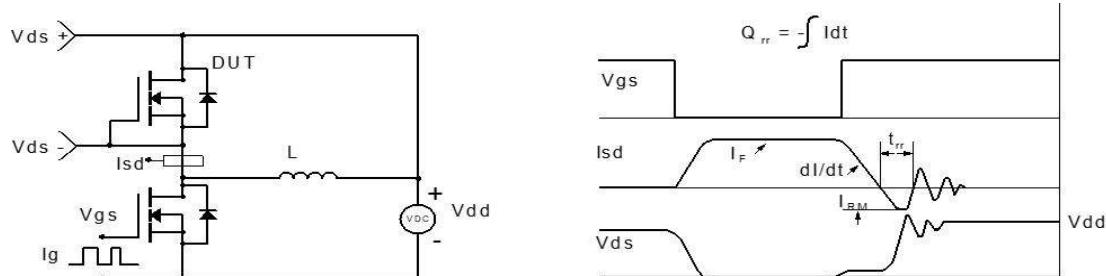
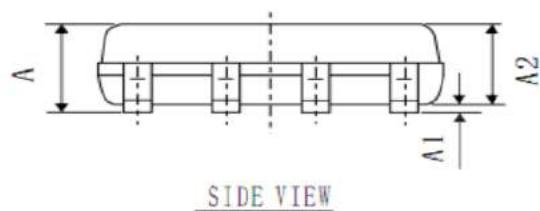
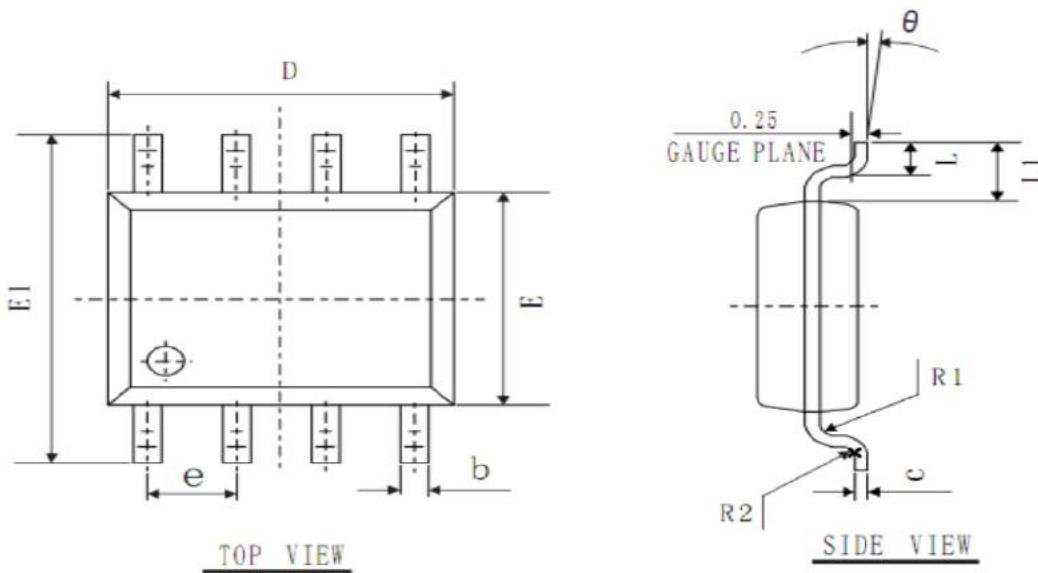


Figure 4: Diode Recovery Test Circuit & Waveform



SOP-8 Package Information



COMMON DIMENSIONS
(UNITS OF MEASURE=mm)

SYMBOL	MIN	NOM	MAX
A	1.40	1.60	1.80
A1	0.05	0.15	0.25
A2	1.35	1.45	1.55
b	0.30	0.40	0.50
c	0.153	0.203	0.253
D	4.80	4.90	5.00
E	3.80	3.90	4.00
E1	5.80	6.00	6.20
L	0.45	0.70	1.00
θ	2°	4°	6°
L1	1.04 REF		
e	1.27 BSC		
R1	0.07 TYP		
R2	0.07 TYP		

Customer Service

Sales and Service:

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